

# UNIVERSAL TEST FIXTURES

3680 Series DC to 60 GHz



The 3680 series provide an accurate, repeatable solution for measuring microstrip and Coplanar substrate devices. Input and output connections are made to the substrate device by two spring-loaded jaws that include coax-to-microstrip/Coplanar launchers. The jaws accommodate substrates from 0.13 to 1.9 mm in thickness. No center section is required. One jaw is movable in two dimensions to accommodate substrates up to 50 mm long (100 mm for 3680-20) and substrates with line offsets of up to 12.7 mm (25 mm for 3680-20). The 3680 series includes three models: the 3680-20 covers DC to 20 GHz with APC-3.5™ connectors, the 3680K covers DC to 40 GHz with Anritsu's K Connector®, and the 3680V covers DC to 60 GHz with Anritsu's V Connector®.

## Features

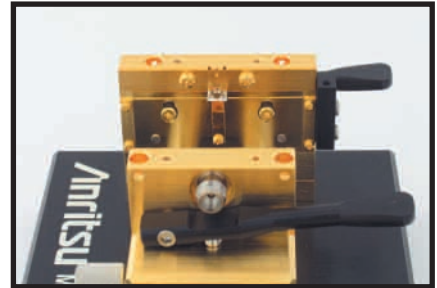
- DC to 60 GHz coverage
- Microstrip and coplanar measurement capability
- Accommodates offset and right-angle test devices
- Calibration/verification kits (optional)
- Substrate measurement capability

## Substrate Measurement Capability

Providing substrate measurement capability for your microstrip or coplanar waveguide designs, the 3680 Series Universal Test Fixtures allow accurate, repeatable transitions from coax to microstrip or coax to coplanar waveguide (CPW). Complete substrate measurement systems comprised of a Universal Test Fixture, a vector or scalar network analyzer, and a "substrate" Calibration Kit can fulfill your microstrip or CPW test needs. Anritsu provides the complete measurement solution, the test fixtures, the calibration kits, and the test equipment for measurements on substrate devices. Our total system responsibility ensures compatible system components, designed to work together properly. Guaranteed system specs provide assurance that your test results are accurate and verifiable.

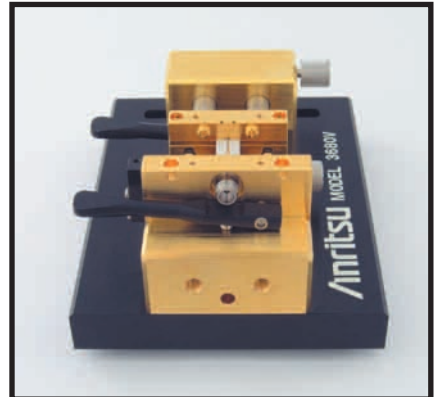
## Universal Test Fixtures

The most critical part of any substrate measurement system is the launching fixture. It must be simple yet flexible, easy to use, and most of all provide accurate, repeatable measurements. Our Universal Test Fixtures are designed to meet these requirements. Three versions of the Universal Test Fixture are available: the 3680-20, DC to 20 GHz; the 3680K, DC to 40 GHz; and the 3680V, DC to 60 GHz. The fixture consists of a fixed connector and a movable connector that can be positioned for substrates up to 2 inches long. No center section is required. The substrate is held in place between springloaded jaws. This allows the fixture to accommodate different devices without requiring a custom center section for each different length. The unique jaw action ensures solid, repeatable electrical contact. The jaw tension is defined by the force of a spring, independent of human judgment errors. This means the tension will always be the same, providing more repeatable measurements. Dielectric rods behind the jaws accurately position the substrate away from the launch to reduce fringing capacitance and contribute to the fixture's excellent repeatability. With a Universal Test Fixture you can be sure your measurements are both accurate and repeatable.



## Microstrip or Coplanar Waveguide Measurements

The unique design of the 3680 provides measurement capability for either microstrip or coplanar waveguide (CPW) designs. All that is required is a simple jaw change. The 3680 does the job of two fixtures, saving you time and money. A substrate measurement system with the 37xxx series



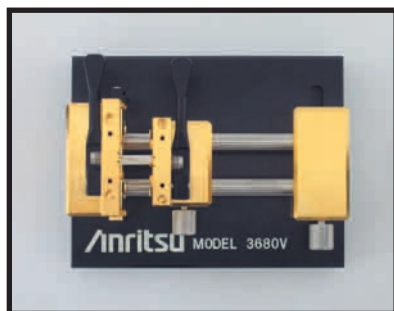
VNA is the only measurement system capable of directly providing microstrip dispersion compensation. Microstrip is a dispersive media - phase shift is not linear with respect to frequency. Our Vector Network Analyzer's ability to compensate for this dispersion can dramatically improve vector measurement accuracy and provide you with the most accurate vector measurements possible.

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## Offset Measurements

With a 3680-based substrate measurement system, there is no need to force your designs into a straight line or leave your designs untested. The 3680 has the ability to offset lines by as much as  $\pm$  inch. Many designs, such as filters, require parallel traces that are offset. In



the past, designers were forced to add extra line lengths, create one-of-a-kind custom fixtures, or worse, not test offset designs. With the flexibility of the 3680, you can test offset or in-line designs with one setup. Formerly-untestable designs can now be tested with ease.

## Right-Angle Measurements

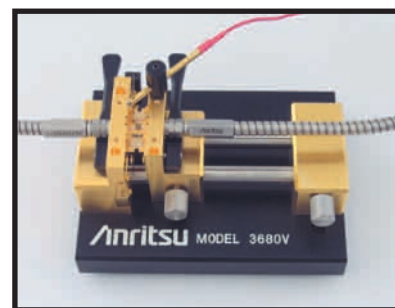
Testing designs with right-angle connections is made easy. The optional rightangle launcher adds a connection at 90° to the fixture. This lets you test devices with right-angle connections with precision and repeatability corresponding to an in-line measurement. The fixture is designed to fit your device; you don't have to design your device to fit the fixture. The right-angle launcher also provides another benefit - the ability to test multiport devices. With the addition of right-angle launchers, the 3680 can become a three port, or even four port launching fixture. A 37xxx series VNA-based microstrip measurement system with optional dual source control can interdependently control up to two sources and a receiver, for testing mixers or other frequency conversion devices. Now a microstrip or CPW mixer, converter, or other device can be tested, with the same convenience as a packaged device.

## 60 GHz Measurements

Anritsu was the first manufacturer to offer a coaxial VNA with continuous 0.04 GHz to 60 GHz measurement capability. With the 3680 Series Universal Test Fixtures, that measurement capability is extended onto the substrate. An Anritsu VNA-based substrate measurement system is capable of measurements from 0.04 GHz to 60 GHz in one setup. And the optional 60 GHz time domain capability provides time or distance measurements with unsurpassed resolution. Discontinuities as close as 1.2 mm on alumina can be resolved. You can measure devices whose performance could previously only be theorized. The 3680V, has excellent return loss and insertion loss from DC to 60 GHz. In a substrate measurement system, that translates to improved accuracy and repeatability, for more accurate characterization of your microstrip or CPW designs.

## Bias Capability

For active device measurements, the 3680 has bias capability either through the RF connection or through a bias probe. With optional multiple bias probes, you can inject bias into any point on your device under test. The bias probe provides infinite placement resolution and eliminates the need for external bias hardware. Alternately, if your active device is biased through an RF connection, bias tees can be used to combine bias and RF at any launch point. The 3680's flexible bias injection eliminates the need for multiple fixtures, saving you time and money. Up to four bias probes can be accommodated.



## MMIC Measurements

With the optional MMIC attachment, you can test MMIC's and very small components as conveniently as other devices. A MMIC attachment consists of a center carrier, with microstrip lines for launching, and cam-operated pressure rods. The MMIC component is placed on the center carrier between microstrip lines. (Machinable center carrier blocks are available for your custom designs.) Contact with the component is made with spring tabs, for reliability and damage protection. The unique design of the MMIC attachment assures solid, repeatable measurements on any small device. An Anritsu substrate measurement system can fulfill all your substrate measurement needs including, with a MMIC attachment, very small substrates and MMICs.

## Calibration/Verification Kits

A full complement of calibration kits for microstrip or coplanar waveguide are available. Standard Open Short Load (OSL) and Line Reflect Line (LRL) calibration components are included. The substrates for these cal kits are carefully selected for proper impedance and consistency, to provide the most accurate measurements possible. Included with every cal kit is a Beatty standard (standard mismatch) and a 20 dB offset termination. Now you can verify, in the fixture, the quality of your calibrations. This verification, available only from Anritsu, ensures the validity of your device measurements.

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## Specifications

3680 series Universal Test Fixture	Substrate types supported	Microstrip or coplanar waveguide
	Overall size	10 x 12.7 x 6.4 cm
	Substrate length	0.5 cm min. 5 cm max. [10 cm with 3680-20]
	Maximum substrate width	No limit
	Substrate thickness	0.012 cm min. 0.19 cm max.
	Maximum line offset	±1.2 cm [±2.5 cm with 3680-20]
	Input and output connectors	3680-20: APC-3.5™ female 3680K: K Connector® female 3680V: V Connector® female
36802 MMIC Attachment	Substrate thickness	0.0 cm, 0.038 cm, 0.064 cm
	Minimum test substrate length	1.5 mm
	Maximum test substrate length	1.17 cm with standard block
	Maximum line offset	±1.2 cm
36801 Right Angle Launcher	Distance from in-line connector, axial	Minimum: 1 cm Maximum: 4 cm
	Distance from in-line connector, offset	Minimum: 0.0 cm Maximum: 2 cm

## Electrical

Model	Universal Test Fixture			Right-Angle Launcher		MMIC Attachment
	3680-20	3680K	3680V	36801K	36801V	36802
Frequency range (GHz)	DC to 20	DC to 40	DC to 60	DC to 30	DC to 50	DC to 60
Return loss (dB) DC to 20 GHz 20 to 40 GHz 40 to 60 GHz	>17	>17 >14	>17 >14 >8	>16 >12	>16 >12 >7	>12 >8 >6
Repeatability (dB) DC to 20 GHz 20 to 40 GHz 40 to 60 GHz	<±0.10	<±0.10 <±0.20	<±0.10 <±0.20 <±0.30	<±0.15 <±0.25	<±0.15 <±0.25 <±0.40	<±0.20 <±0.40 <±0.60

Temperature range: -20° to 70°C

## Ordering information

Please specify model/order number, name and quantity when ordering.

Model/Order No.	Name
<b>Main frame</b>	
3680-20	Universal Test Fixture (20 GHz)
3680K	Universal Test Fixture (40 GHz)
3680V	Universal Test Fixture (60 GHz)
<b>Accessories</b>	
36801K	Right-Angle Launcher (30 GHz)
36801V	Right-Angle Launcher (50 GHz)
36802	MMIC Attachment
36803	Bias Probe
36805-10M	10 mil launchers <sup>①</sup>
36805-15M	15 mil launchers <sup>①</sup>
36805-25M	25 mil launchers <sup>①</sup>
<b>Calibration/verification kits</b>	
36804B-10M	10 mil microstrip cal/verif. kit, DC to 50 GHz
36804B-15M	15 mil microstrip cal/verif. kit, DC to 30 GHz
36804B-25M	25 mil microstrip cal/verif. kit, DC to 15 GHz
36804-25C	25 mil coplanar waveguide cal/verif. kit, DC to 20 GHz

① 36805 series includes (4) substrate launchers for the 36802 MMIC attachment